



**DSD'2009**  
**EUROMICRO CONFERENCE ON**  
**DIGITAL SYSTEM DESIGN**  
**Architectures, Methods and Tools**  
**August 27-29, 2009, Patras, Greece**  
**Call for Papers**

**Session Chair:**

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*Special Session: SS6 (DTD)*

**DEPENDABILITY AND TESTING OF DIGITAL SYSTEMS**

**BACKGROUND**

The Euromicro Conference on Digital System Design addresses all aspects of (embedded) digital and mixed hardware/software system engineering. It is a discussion forum for researchers and engineers working on state-of-the-art investigations, development, and applications. It focuses on advanced system design and design automation concepts, paradigms, methods and tools, as well as modern implementation technologies. Every system has to be tested several times during its life period - during its development, production and its actual use. The need for testing strictly depends on the actual use of the system, e.g., if the system can be repaired or not, if the system must be safe, etc. The design must reflect these requirements.

**SCOPE**

The special session on "Dependability and Testing of Digital Systems" addresses emerging issues, hot problems, new solution methods and their hardware and software implementations in all fields of digital and mixed-signal system dependability and testing. It is especially focused on the dependability and testing related to the SoC technology and modern embedded applications:

- Built-in Self-Test: off-line BIST and on-line BIST
- SoC and NoC Testing
- Error Detection and Correction
- Testability Analysis
- Scan-based techniques
- IDDQ and Current Testing
- Synthesis for Testability
- Diagnosis & Testing of Embedded Systems
- Analog, Mixed-Signal and RF Testing
- Memory and Processor Testing
- System Diagnosis

**SUBMISSION OF PAPERS**

Prospective authors are encouraged to submit their manuscripts for review electronically through the following web page (<http://www.conftool.net/dsd2009/>) or by sending the paper to the Session Organizer via email [kubatova@fel.cvut.cz](mailto:kubatova@fel.cvut.cz) (only in the case of the web access problem) before the deadline for submission (please indicate the topic area as: SS6). Each manuscript should include the complete paper text, all illustrations, and references. The manuscript should conform to the required format: single-spaced, double column, A4/US letter page size, 10-point size Times Roman font, up to 8 pages. **In order to conduct a blind review, no indication of the authors' names should appear in the submitted manuscript.**

The DSD'2009 web page should be consulted for the exact submission format.

The Proceedings of DSD'2009 will be published by the IEEE Computer Society.

**IMPORTANT DATES**

Submission of papers: **March 27, 2009**

Notification of acceptance: April 27, 2009

Camera ready papers: May 26, 2009

**SS6 webpage:** <http://dsd09.felk.cvut.cz/test/>

**Euromicro webpage:** <http://www.euromicro.org>

**DSD web page:** <http://www.iuma.ulpgc.es/dsd09>